

IN THE CLAIMS

1. (currently amended) A method for inspecting a component, said method comprising:

coupling the component to a fixture such that the component is fixedly secured in position during machining ~~of the component; and~~ of the component;

inspecting the component using an inspection tool while the component is coupled to the fixture, wherein the inspection tool includes a probe having at least a first and a ~~second probe tip~~ that are each selectively positionable with respect to each other. second probe tip;

positioning the first probe tip relative to the component; and

positioning the second probe tip relative to the component and relative to the first probe tip wherein the first probe tip is slideably coupled to the probe, and the second probe tip is slideably coupled to the probe.

2. (original) A method in accordance with Claim 1 wherein coupling the component to a fixture further comprises machining the component using a machining apparatus while the component is coupled to the fixture.

3. (original) A method in accordance with Claim 2 wherein inspecting the component further comprises coupling the inspection tool to at least one of the fixture and the machining apparatus.

4. (original) A method in accordance with Claim 1 wherein inspecting the component further comprises measuring at least one of a thickness and a length of the component.

5. (previously presented) A method in accordance with Claim 1 wherein inspecting the component further comprises measuring a thickness of the component using the first and the second probe tips.

6. (original) A method in accordance with Claim 5 wherein measuring a thickness of the component comprises:

positioning the first probe tip in contact with a first surface of the component;

positioning the second probe tip in contact with a second surface of the component; and

determining a thickness of the component using the location of the first probe tip and the location of the second probe tip.